

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

248760USORDCONT

SERIAL NO.

New Continuation of
10/188,744

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Yasuo OHBA

FILING DATE

Herewith

2/9/04

GROUP

2822

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>MD</i>	AA	4,792,958	12/20/88	OHBA, et al.	392	45	
	AB	4,809,287	02/28/89	OHBA, et al.	392	45	
	AC	4,835,117	05/30/89	OHBA, et al.	439	40	
	AD	4,949,349	08/14/90	OHBA, et al.	392	45	
	AE	4,910,743	03/20/90	OHBA, et al.	392	45	
	AF	4,928,285	05/22/90	KUSHIBE, et al.	392	45	
	AG	4,893,313	01/09/90	HATAKOSHI, et al.	392	46	
	AH	5,076,800	12/31/91	MILNES, et al.	439	394	
	AI	5,036,521	07/30/91	HATAKOSHI, et al.	562	509	
	AJ	5,168,077	12/01/92	ASHIZAWA, et al.	501	71	
	AK	5,042,043	08/20/91	HATANO, et al.	426	72	
	AL	5,005,057	04/02/91	IZUMIYA, et al.	257	13	
	AM	5,079,184	01/07/92	HATANO, et al.	117	102	
<i>MD</i>	AN	5,103,271	04/07/92	IZUMIYA, et al.	257	94	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO	2000-34588	04/28/00	JAPAN		
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	Y. OHBA, et al., Japanese Journal of Applied Physics, Vol. 37 Part 2, No. 8A, pp. L 905 - L 906, "FABRICATION AND CHARACTERIZATION OF AlGaIn/GaN DOUBLE-HETEROLASER STRUCTURES ON SAPPHIRE SUBSTRATES USING SINGLE CRYSTALLINE AlN BUFFER LAYERS," August 1, 1998.
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

William M. Soura

Date Considered

3-29-05

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
ONE	AA	5,228,044	07/13/93	OHBA	392	45	
	AB	5,235,194	08/10/93	IZUMIYA, et al.	257	13	
	AC	5,273,933	12/28/93	HATANO, et al.	119	89	
	AD	5,317,167	05/31/94	IZUMIYA, et al.	257	13	
	AE	5,432,808	07/11/95	HATANO, et al.	392	45	
	AF	5,617,438	04/01/97	HATANO, et al.	392	45	
	AG	5,740,192	04/14/98	HATANO, et al.	392	45	
	AH	5,998,810	12/07/99	HATANO, et al.	257	102	
	AI	6,242,764	06/05/01	Y. OHBA, et al.	257	190	
	AJ	5,990,495	11/23/99	Y. OHBA	257	94	
	AK	5,656,832	06/01/99	Y. OHBA, et al.	257	190	
ONE	AL	5,909,040	06/01/99	Y. OHBA, et al.	257	190	
	AM	5,929,466	07/27/99	Y. OHBA, et al.	257	103	
	AN						

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					YES	NO
	AO					
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	AX	
	AY	
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>MS</i>	AA	5,146,465	09/92	KHAN, et al.	585	516	
	AB	6,259,122	07/01	OTA, et al.	257	101	
	AC	5,875,052	02/99	SHMAGIN, et al.	359	244	
	AD	6,306,672 B1	10/01	KIM	438	22	
	AE	6,046,464	04/00	SCHETZINA	257	96	
	AF	6,440,823 B1	08/02	VAUDO, et al.	438	498	
	AG	5,929,467	07/99	KAWAI, et al.	257	192	
<i>MS</i>	AH	5,923,058	07/99	AGARWAL, et al.	257	198	
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

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